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Contents

MACHINE LEARNING AND CLASSIFICATION

- 11787 03 **Data augmentation and pre-trained networks for extremely low data regimes unsupervised visual inspection (Invited Paper) [11787-1]**
- 11787 04 **On evaluating deep learning-based optical flow methods for gas velocity estimation with optical gas imaging cameras [11787-2]**
- 11787 05 **Explainability of deep learning classifier decisions for optical detection of manufacturing defects in the automated fiber placement process [11787-3]**
- 11787 06 **Evaluation of thermography-based automated delamination and cavity detection in concrete bridges [11787-4]**
- 11787 07 **Sequential concrete crack segmentation using deep fully convolutional neural networks and data fusion [11787-5]**

IMAGE-BASED MEASUREMENT TECHNOLOGY

- 11787 08 **The effects of pattern screen surface deformation on deflectometric measurements: a simulation study [11787-6]**
- 11787 09 **Multimodal measurement system for road analysis and surveying of road surroundings [11787-7]**
- 11787 0A **Irritation-free optical 3D-based measurement of tidal volume [11787-8]**
- 11787 0B **A GPU-based ray tracing approach for the prediction of multireflections on measurement objects and the a priori estimation of low-reflection measurement poses [11787-9]**
- 11787 0D **Experimental setup for fast VIS-NIR spectroscopy measurements in deflagrations [11787-11]**

POSTER SESSION

- 11787 0E **Classification of municipal solid waste using deep convolutional neural network model applied to multispectral images [11787-12]**
- 11787 0G **Qualification of holistic and generic camera-system calibration by fringe projection [11787-14]**
- 11787 0H **Vision threads: a novel approach to generic camera calibration [11787-15]**

- 11787 0I **Effective deep learning training method using blur and noise filter to detect defect in TFT-LCD PAD** [11787-16]
- 11787 0K **Improving light efficiency in multispectral imaging via complementary notch filters** [11787-18]
- 11787 0L **Deep learning for automated focus quality detection in wafer inspection** [11787-19]
- 11787 0M **Deep learning model and train method to increase the speed and accuracy in inline TFT-PAD area inspection** [11787-20]
- 11787 0N **Nonlinear response of high speed infrared electronic devices: calibration for high temperatures** [11787-21]
- 11787 0P **Automated visual inspection of fabric image using deep learning approach for defect detection** [11787-23]
- 11787 0R **Development of a smartphone-based augmented reality device for industrial tasks** [11787-25]
- 11787 0S **Comparison of Unet and Mask R-CNN for impact damage segmentation in lock-in thermography phase images** [11787-26]